Memory Structures

Ramon Canal NCD - Master MIRI

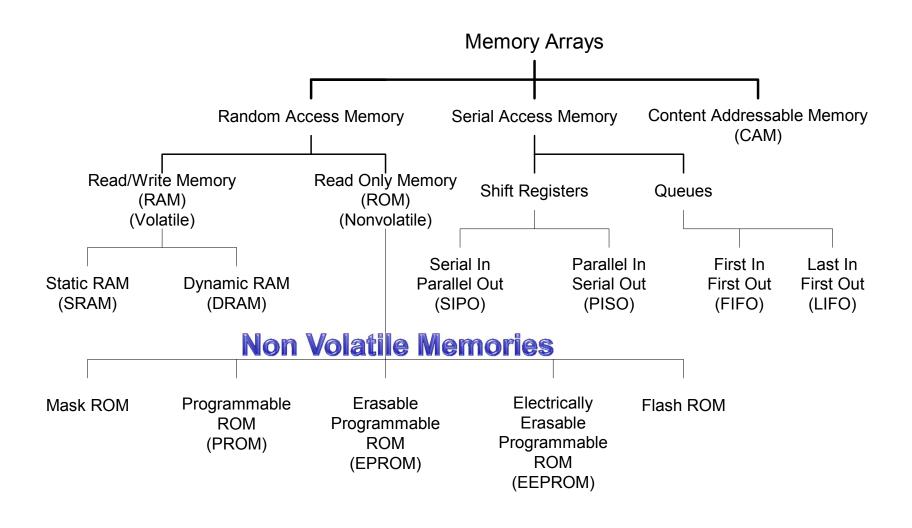
Slides based on:Introduction to CMOS VLSI Design. D. Harris



Outline

- Memory Arrays
- SRAM Architecture
 - SRAM Cell
 - Decoders
 - Column Circuitry
 - Multiple Ports
- Serial Access Memories

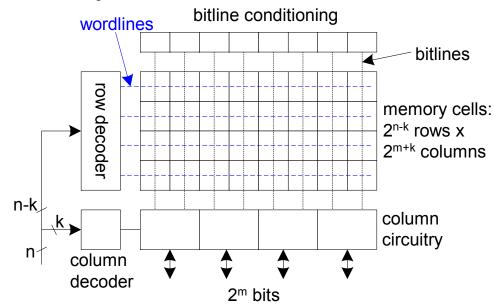
Memory Arrays





Array Architecture

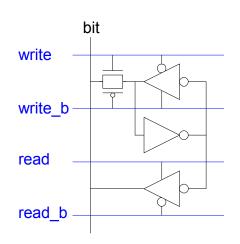
- 2ⁿ words of 2^m bits each
- If n >> m, fold by 2^k into fewer rows of more columns

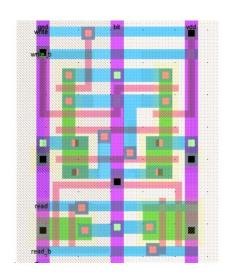


- Good regularity easy to design
- Very high density if good cells are used

12T SRAM Cell

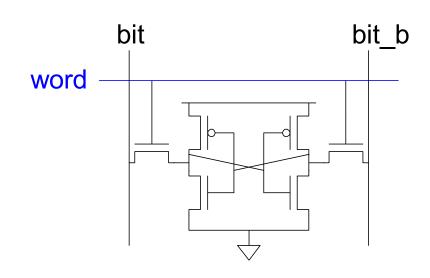
- Basic building block: SRAM Cell
 - Holds one bit of information, like a latch
 - Must be read and written
- 12-transistor (12T) SRAM cell
 - Use a simple latch connected to bitline
 - $-46 \times 75 \lambda$ unit cell





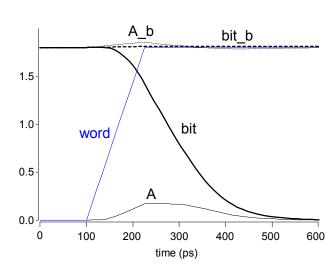
6T SRAM Cell

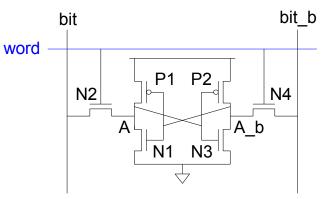
- Cell size accounts for most of array size
 - Reduce cell size at expense of complexity
- 6T SRAM Cell
 - Used in most commercial chips
 - Data stored in cross-coupled inverters
- Read:
 - Precharge bit, bit_b
 - Raise wordline
- Write:
 - Drive data onto bit, bit b
 - Raise wordline



SRAM Read

- Precharge both bitlines high
- Then turn on wordline
- One of the two bitlines will be pulled down by the cell
- Ex: A = 0, $A_b = 1$
 - bit discharges, bit_b stays high
 - But A bumps up slightly
- Read stability
 - A must not flip





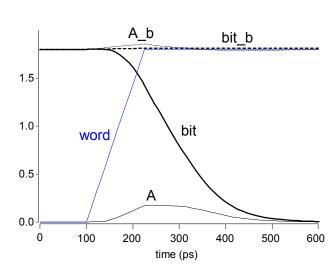


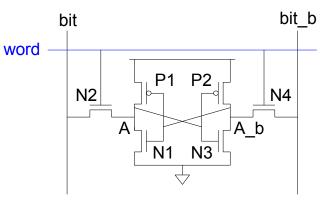
Departament d'Arquitectura

de Computadors

SRAM Read

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- Then turn on wordline
- One of the two bitlines will be pulled down by the cell
- Ex: A = 0, $A_b = 1$
 - bit discharges, bit_b stays high
 - But A bumps up slightly
- Read stability
 - A must not flip
 - N1 >> N2

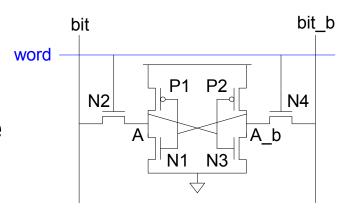


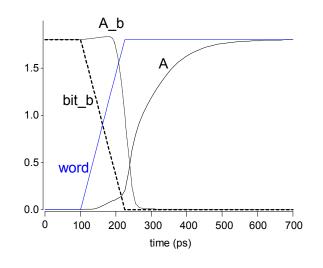




SRAM Write

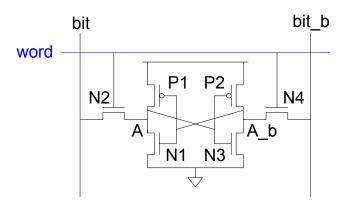
- Drive one bitline high, the other low
- Then turn on wordline
- Bitlines overpower cell with new value
- Ex: A = 0, A_b = 1, bit = 1, bit_b = 0
 - Force A_b low, then A rises high
- Writability
 - Must overpower feedback inverter

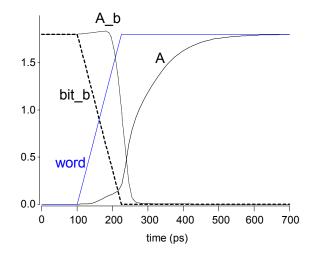




SRAM Write

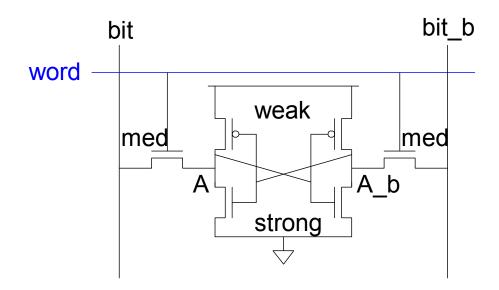
- Drive one bitline high, the other low
- Then turn on wordline
- Bitlines overpower cell with new value
- Ex: A = 0, A_b = 1, bit = 1, bit_b = 0
 - Force A b low, then A rises high
- Writability
 - Must overpower feedback inverter
 - N2 >> P1





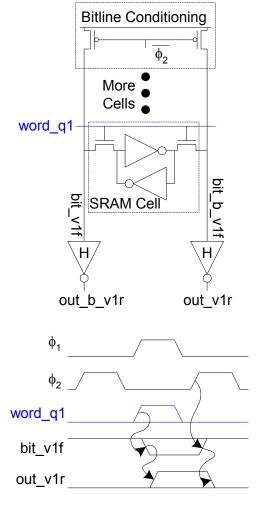
SRAM Sizing

- High bitlines must not overpower inverters during reads
- But low bitlines must write new value into cell

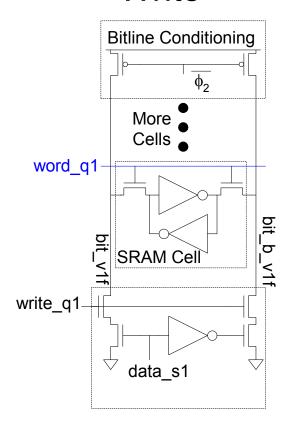


SRAM Column Example

Read

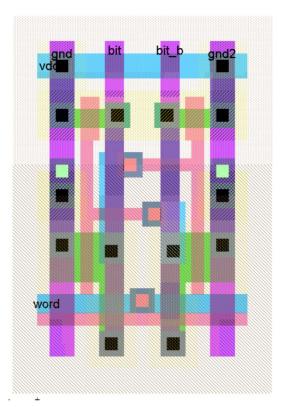


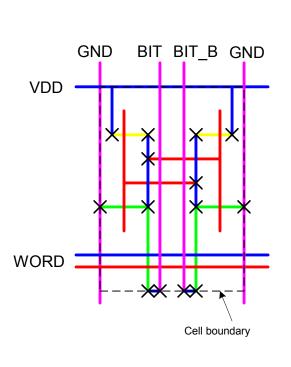
Write

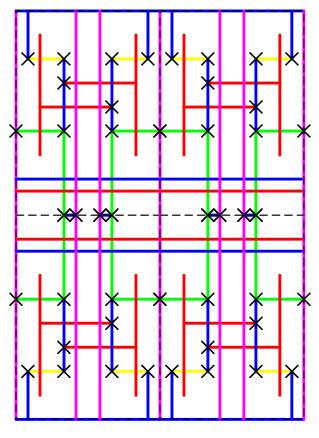


SRAM Layout

- Cell size is critical: 26 x 45 λ (even smaller in industry)
- Tile cells sharing V_{DD}, GND, bitline contacts







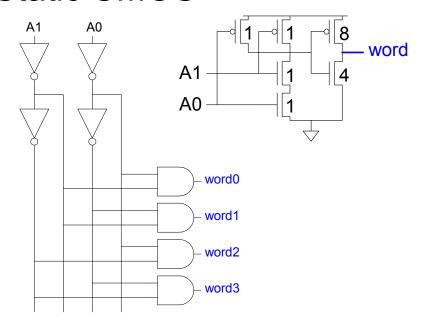
Periphery

- ☐ Decoders
- Sense Amplifiers
- ☐ Input/Output Buffers
- Control / Timing Circuitry

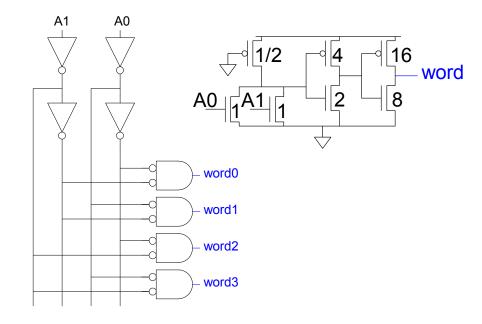
Decoders

- n:2ⁿ decoder consists of 2ⁿ n-input AND gates
 - One needed for each row of memory
 - Build AND from NAND or NOR gates

Static CMOS



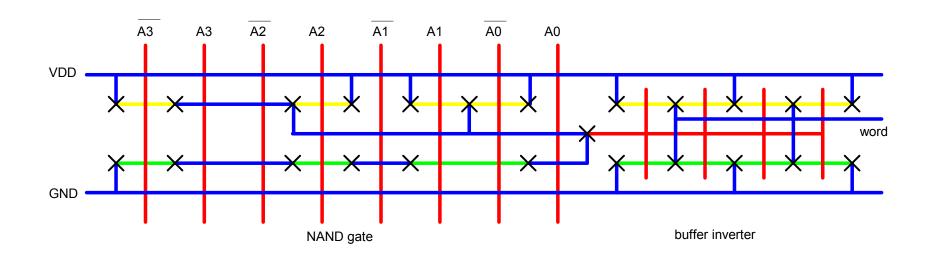
Pseudo-nMOS





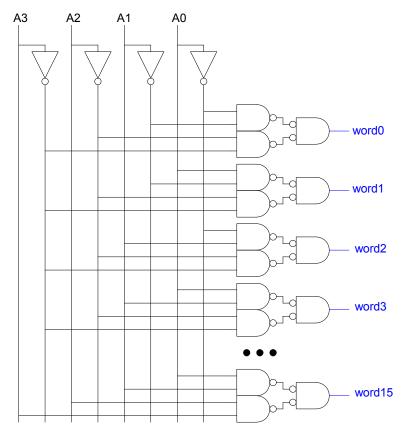
Decoder Layout

- Decoders must be pitch-matched to SRAM cell
 - Requires very skinny gates



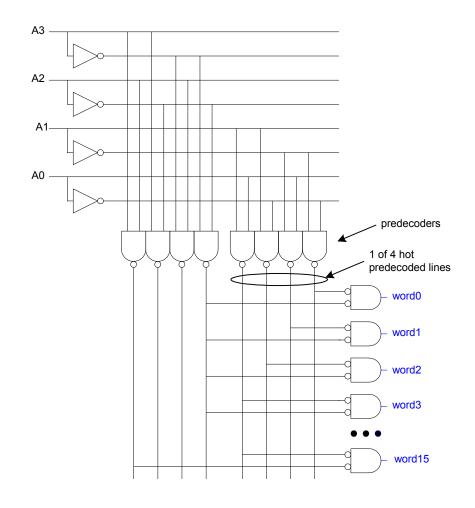
Large Decoders

- For n > 4, NAND gates become slow
 - Break large gates into multiple smaller gates



Predecoding

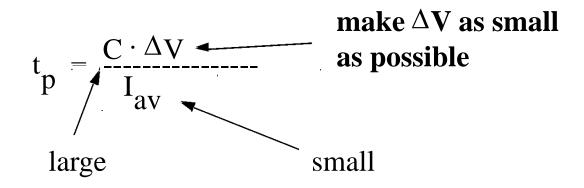
- Many of these gates are redundant
 - Factor out common gates into predecoder
 - Saves area
 - Same path effort



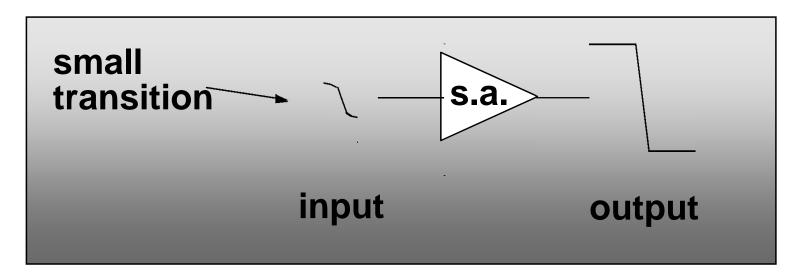
Periphery

- Decoders
- □ Sense Amplifiers
- ☐ Input/Output Buffers
- Control / Timing Circuitry

Sense Amplifiers



Idea: Use Sense Amplifer

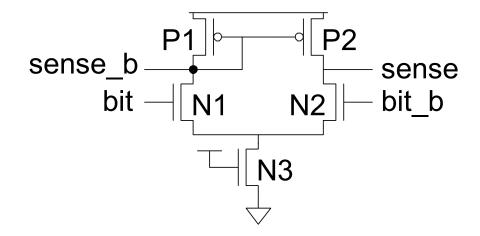


Sense Amplifiers

- Bitlines have many cells attached
 - Ex: 32-kbit SRAM has 256 rows x 128 cols
 - 128 cells on each bitline
- $t_{pd} \propto (C/I) \Delta V$
 - Even with shared diffusion contacts, 64C of diffusion capacitance (big C)
 - Discharged slowly through small transistors (small I)
- Sense amplifiers are triggered on small voltage swing (reduce ΔV)

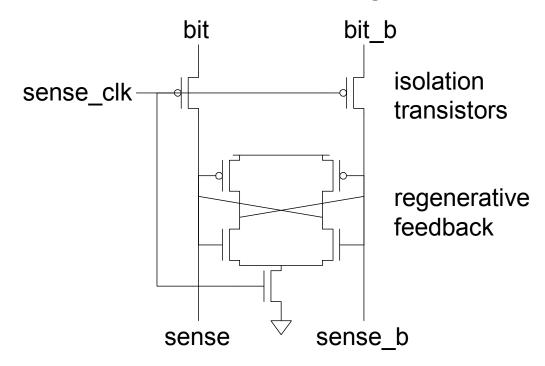
Differential Pair Amp

- Differential pair requires no clock
- But always dissipates static power



Clocked Sense Amp

- Clocked sense amp saves power
- Requires sense_clk after enough bitline swing
- Isolation transistors cut off large bitline capacitance



Periphery

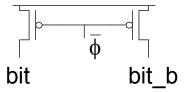
- Decoders
- Sense Amplifiers
- ☐ Input/Output Buffers
- ☐ Control / Timing Circuitry

Column Circuitry

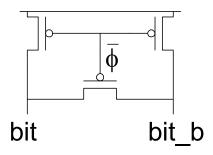
- Some circuitry is required for each column
 - Bitline conditioning
 - Column multiplexing

Bitline Conditioning

Precharge bitlines high before reads

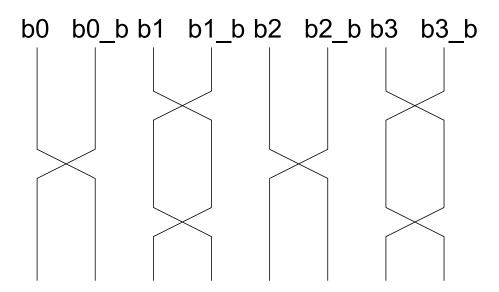


Equalize bitlines to minimize voltage difference when using sense amplifiers



Twisted Bitlines

- Sense amplifiers also amplify noise
 - Coupling noise is severe in modern processes
 - Try to couple equally onto bit and bit_b
 - Done by twisting bitlines

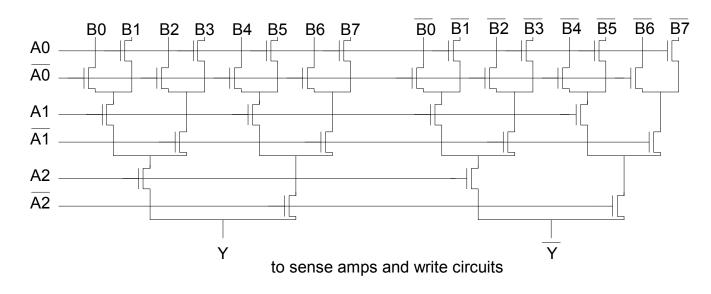


Column Multiplexing

- Recall that array may be folded for good aspect ratio
- Ex: 2 kword x 16 folded into 256 rows x 128 columns
 - Must select 16 output bits from the 128 columns
 - Requires 16 8:1 column multiplexers

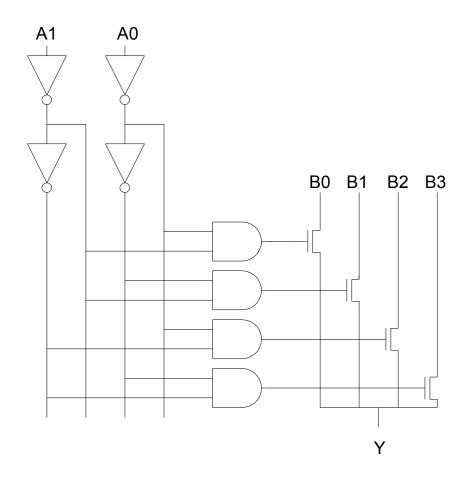
Tree Decoder Mux

- Column mux can use pass transistors
 - Use nMOS only, precharge outputs
- One design is to use k series transistors for 2^k:1 mux
 - No external decoder logic needed

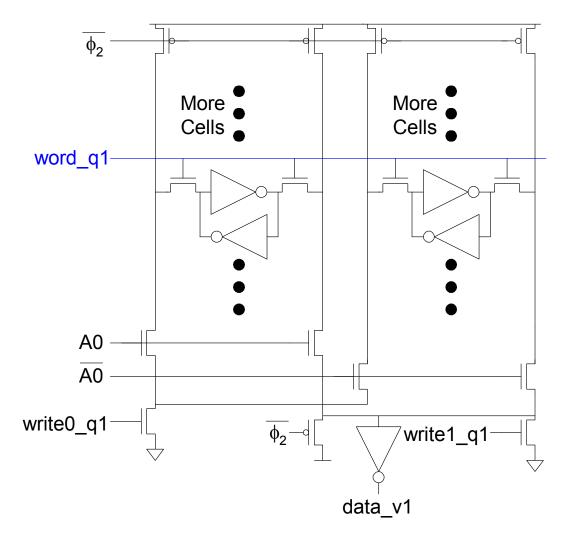


Single Pass-Gate Mux

Or eliminate series transistors with separate decoder



Ex: 2-way Muxed SRAM



Memory configurations

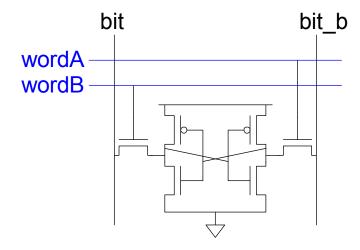
- ☐ Multiported memories
- □ CAM Memories
- ☐ Serial Access, Queues

Multiple Ports

- We have considered single-ported SRAM
 - One read or one write on each cycle
- Multiported SRAM are needed for register files
- Examples:
 - Multicycle processor must read two sources or write a result on some cycles
 - Pipelined processor must read two sources and write a third result each cycle
 - Superscalar processor must read and write many sources and results each cycle

Dual-Ported SRAM

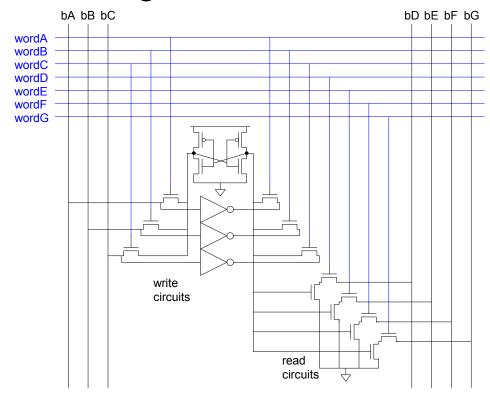
- Simple dual-ported SRAM
 - Two independent single-ended reads
 - Or one differential write



- Do two reads and one write by time multiplexing
 - Read during ph1, write during ph2

Multi-Ported SRAM

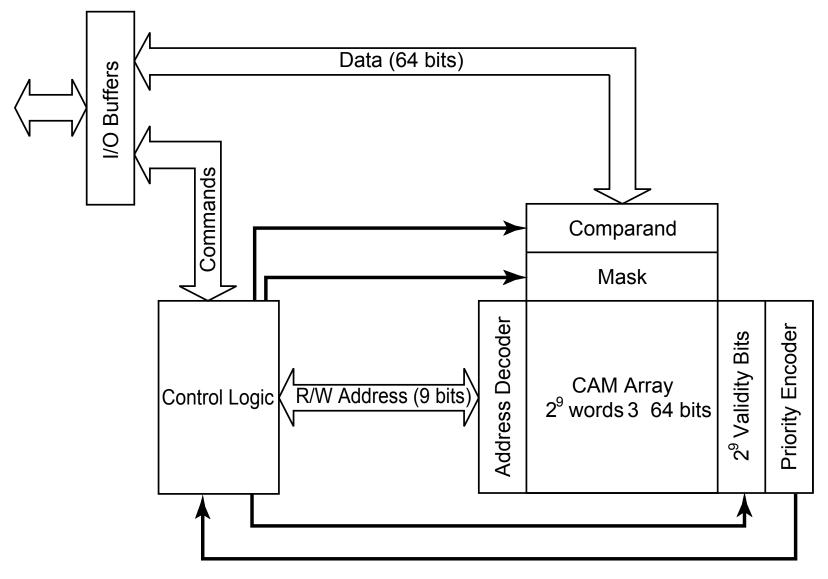
- Adding more access transistors hurts read stability
- Multiported SRAM isolates reads from state node
- Single-ended design minimizes number of bitlines



Memory configurations

- ☐ Multiported memories
- □ CAM Memories
- ☐ Serial Access, Queues

Contents-Addressable Memory



Memory configurations

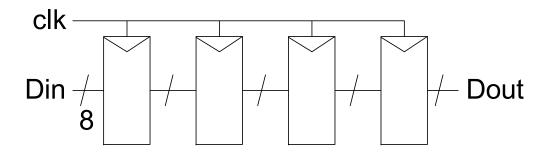
- ☐ Multiported memories
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Serial Access Memories

- Serial access memories do not use an address
 - Shift Registers
 - Tapped Delay Lines
 - Serial In Parallel Out (SIPO)
 - Parallel In Serial Out (PISO)
 - Queues (FIFO, LIFO)

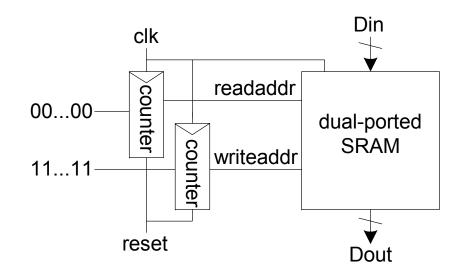
Shift Register

- Shift registers store and delay data
- Simple design: cascade of registers
 - Watch your hold times!



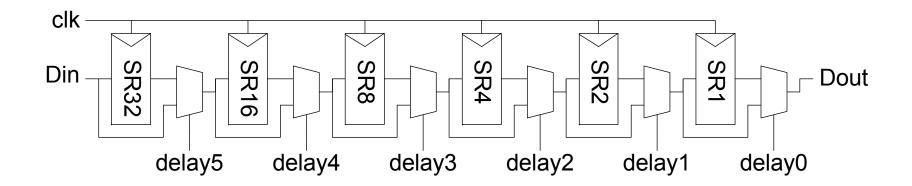
Denser Shift Registers

- Flip-flops aren't very area-efficient
- For large shift registers, keep data in SRAM instead
- Move read/write pointers to RAM rather than data
 - Initialize read address to first entry, write to last
 - Increment address on each cycle



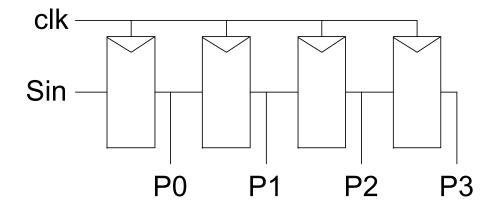
Tapped Delay Line

- A tapped delay line is a shift register with a programmable number of stages
- Set number of stages with delay controls to mux
 - Ex: 0 63 stages of delay



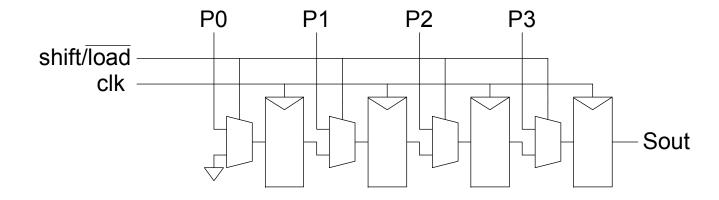
Serial In Parallel Out

- 1-bit shift register reads in serial data
 - After N steps, presents N-bit parallel output



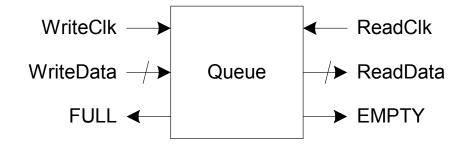
Parallel In Serial Out

- Load all N bits in parallel when shift = 0
 - Then shift one bit out per cycle



Queues

- Queues allow data to be read and written at different rates.
- Read and write each use their own clock, data
- Queue indicates whether it is full or empty
- Build with SRAM and read/write counters (pointers)



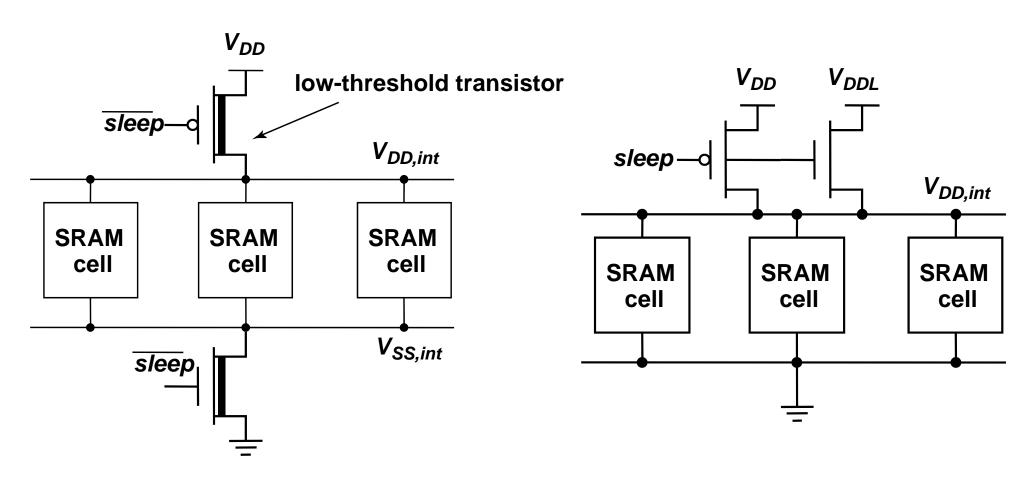
FIFO, LIFO Queues

- First In First Out (FIFO)
 - Initialize read and write pointers to first element
 - Queue is EMPTY
 - On write, increment write pointer
 - If write almost catches read, Queue is FULL
 - On read, increment read pointer
- Last In First Out (LIFO)
 - Also called a stack
 - Use a single stack pointer for read and write

Other considerations

- ☐ Leakage control
- Redundancy
- ☐ Flash Memories

Suppressing Leakage in SRAM



Inserting Extra Resistance

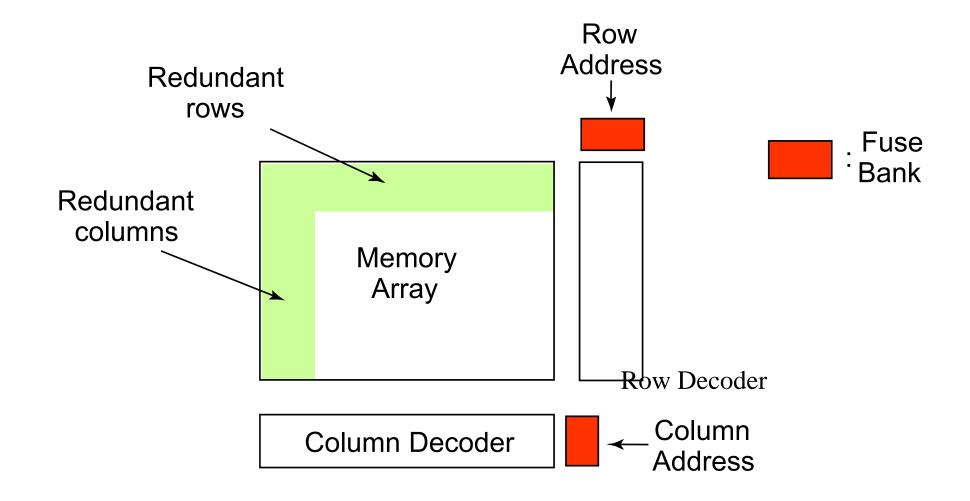
Reducing the supply voltage



Other considerations

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Redundancy



Error-Correcting Codes

Example: Hamming Codes

$$P_1 P_2 B_3 P_4 B_5 B_6 B_7$$

e.g. B3 Wrong

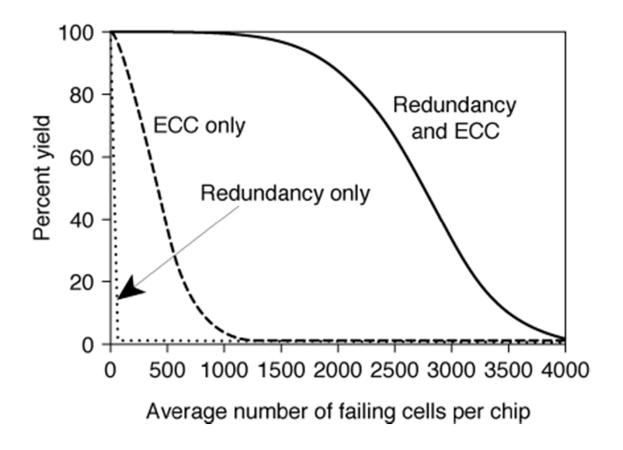
with

$$P_1 \oplus B_3 \oplus B_5 \oplus B_7 = 0$$

$$P_2 \oplus B_3 \oplus B_6 \oplus B_7 = 0$$

$$P_4 \oplus B_5 \oplus B_6 \oplus B_7 = 0$$

Redundancy and Error Correction

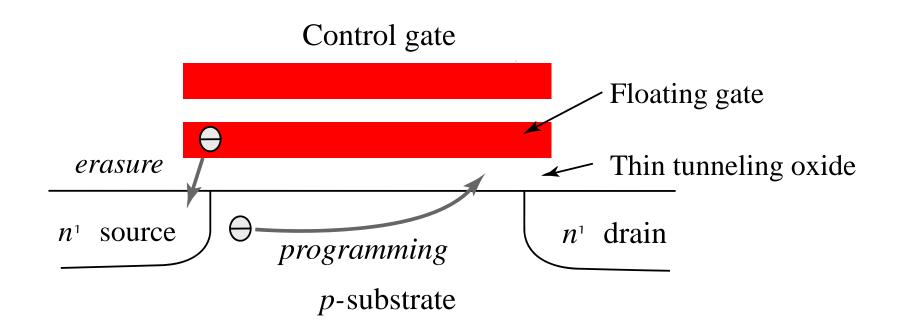




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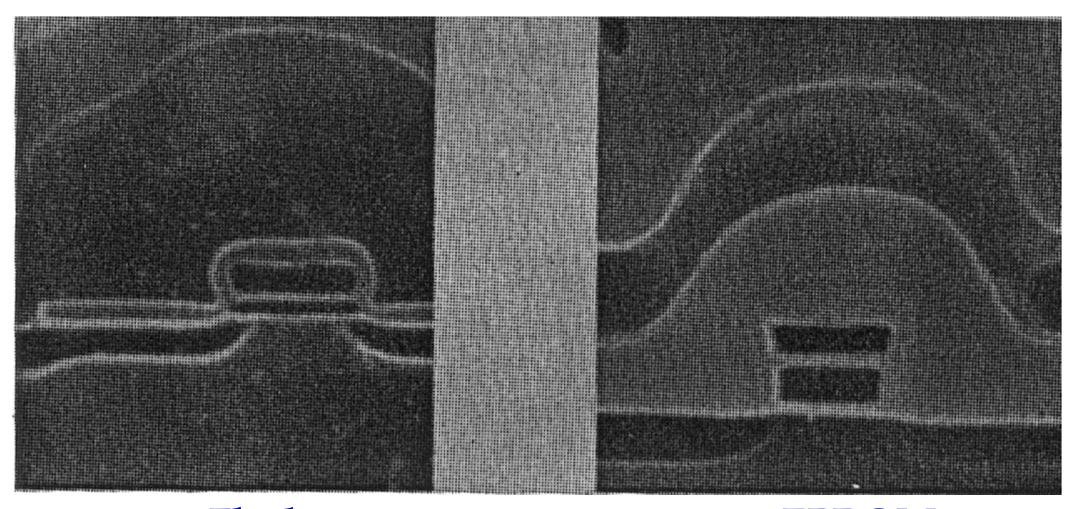
Flash EEPROM



Many other options ...



Cross-sections of NVM cells

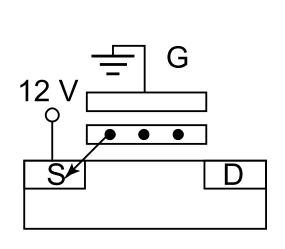


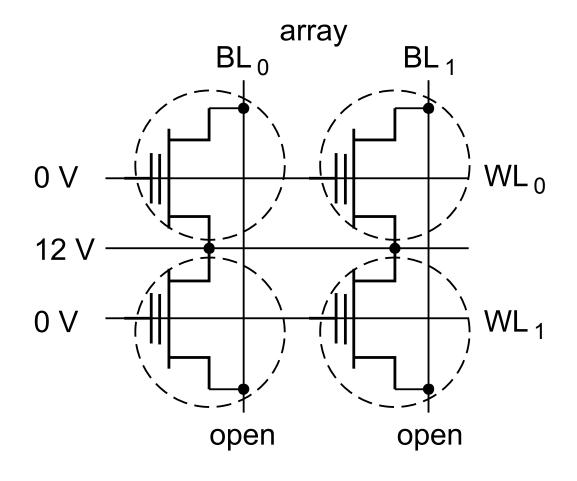




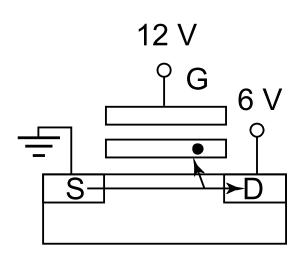
Basic Operations in a NOR Flash Memory— Erase

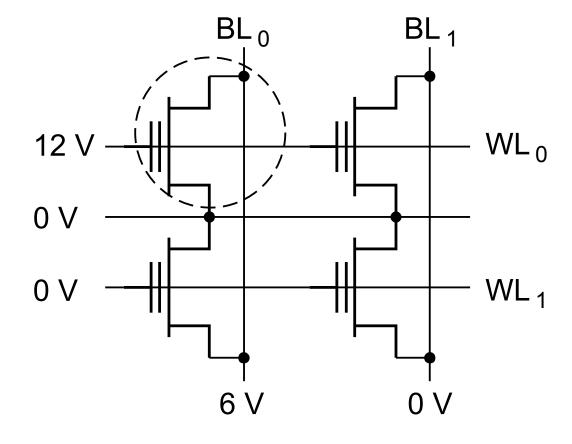
cell



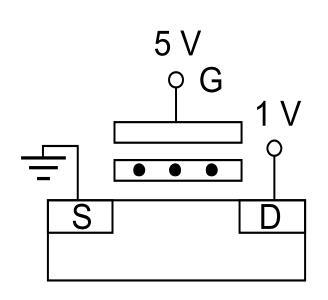


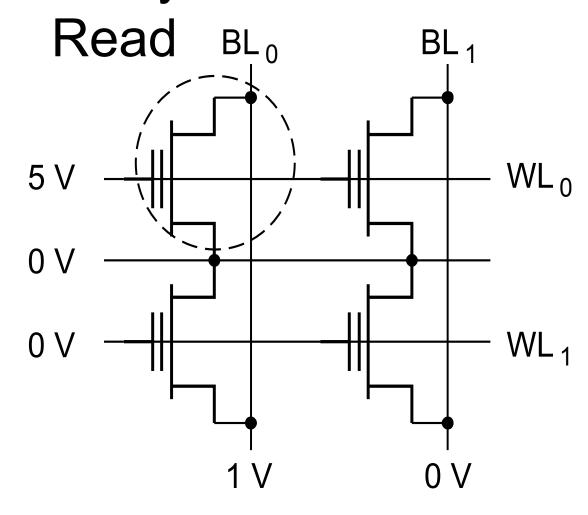
Basic Operations in a NOR Flash Memory— Write





Basic Operations in a NOR Flash Memory—





Conclusions

Memory Structure:

